

Notice of References Cited	Application/Control No. 10/668,714	Applicant(s)/Patent Under Reexamination ORLOWSKI ET AL.	
	Examiner Julio J. Maldonado	Art Unit 2823	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,352,903 B1	03-2002	Rovedo et al.	438/387
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*	N	2 799 307	01-1999	France	Bois et al.	H 01 L 29/786
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NON-PATENT DOCUMENTS

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	U	Monfray et al., First 80nm SON (Silicon-On-Nothing) MOSFETS with perfect morphology and high electrical performance, IEEE, pp. 29.7.1-29.7.4 (2001).
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.